

Assessment of Accelerated Stress Testing Data for Silicon Photovoltaics using Tensor Decomposition Methods

Project Overview

The photovoltaic (PV) industry is simultaneously targeting long warranties and new materials/designs for high-energy-yield modules, requiring an advanced methodology to forecast long-term durability of products with un-proven materials combinations. Extended, sequential, and combined stress testing methods are gaining popularity for assessing durability of PV modules/materials beyond the early-stage mortalities. Importantly, multiple degradation mechanisms can proceed simultaneously, and their separate contributions to the overall power loss should ideally be quantified. This work examines the use of data-driven tools towards developing a strategy for faster learning cycles in accelerated stress testing.

DuraMAT

- **Goal:** Characterize and quantify the evolution of distinct degradation modes in silicon PV modules undergoing accelerated stress testing
- **Approach:** Leverage two-dimensional matrix and higher-order tensor decompositions to extract interpretable modes from image stacks across accelerated stress testing stages

Data Decomposition Methods

- SVD computes an orthogonal, rank-1 decomposition of matrix1
- Decomposition modes are ordered and quantified by their contributions to the original matrix
- Foundational technique for principal component analysis (PCA) and proper orthogonal decomposition (POD)

• Tucker decomposition generalizes the SVD to higher-order tensors by replacing singular values with a smaller (but dense) tensor of the same order as original^{3,4}

Data Details

packaging structures

• Difficult to quantify contributions of modes to different dimensions of the data

Singular Value Decomposition (SVD) Tucker Decomposition Canonical Polyadic Decomposition

Andrew Glaws and Dana B. Kern *National Renewable Energy Laboratory*

Modified IEC TS 63209-2:2022 sequential stress procedure:

Investigated 8 mini-modules with varying encapsulant and

 A3: Full-spectrum light exposure under 65 C chamber temperature, 90 C black panel temperature, 0.8 W/m2-nm intensity at 340nm,

 TC50: Thermal cycling from 85 to -40 C with ramp rates defined in IEC 61215, and current injection equivalent to short-circuit current HF10: Humidity-freeze for 10 cycles between 85 C with 85 %-RH and -40 C

• Data obtained from "Degradation Pathways in Glass/Glass Bifacial PV With Emerging Encapsulants and Half-Cut Cells" DuraMAT project

DH200:Damp heat for 200 hours with 85 C and 85%-RH

• Photoluminescence (PL) images (808nm light, 1 Sun) • Electroluminescence (EL) images (0.9A and 9A)

and 20 %-RH for 2000 hours

• Current-Voltage (IV) metrics

with non-controlled humidity

- Reduces the Tucker decomposition by assuming central tensor is super-diagonal^{3,5}
- Decomposes full tensor into sum of rank-1 tensors • Contributions of modes to different dimensions of the data
- are easily extracted from mode vector norm

Interpreting Modal Decompositions The Correlating Modes with Performance Metrics SVD SVD Tucker Decomposition Fill Factor Mode 50 Mode 32 Mode 24 Mode 34 $\frac{5}{6}$ 0.85 P <00 xx10 xx200 CP Decomposition example of the state of the state Modes of the Short-circuit Current Mode 20 Mode 7 Mode 33 Mode 9 $\frac{8}{3}$ 0.96 A TOO WAS ONTO P 250 450 1200 VT UU • Fill factor degradation exhibit stronger correlations with identified linear modes than short-circuit current • SVD can only consider a single parameter at time and modes do not exhibit physical

- relationships with data
- Tucker captures evolutions along different parameters but are not easily interpretable
- CP modes can be explicitly quantified in terms of their contributions to each parameter

Outcome & Impact

- Tensor approaches identify and isolate meaningful degradation modes from stress testing datasets • Compared tensor decompositions to matrix-based SVD, which produces efficient modes for data reconstruction but provide limited interpretability
- Tensor-based approach enables the consideration of multiple imaging types, stressing procedures, module characteristics, etc.
- Generalizable methods can be used to characterize degradation across many materials and devices Correlate contributions of CP modes to IV metrics across stress testing stages
- Delamination and cracking modes correlate most strongly with evolution of fill factor during testing and highlight appearance in PL and high-current EL imagining
- Short-circuit current showed weaker correlation with linear modes and may require more complex methods to identify key drivers of performance degradation

• Correlated modes highlight delamination found PL images for glass/transparent-backsheet modules and cracking found in the high-current EL images for glass/glass modules

• Modes for short-circuit current vary more in highlighted degradations, including crowding features and delamination modes

References

- 1. V. Klema and A. Laub, "The singular value decomposition: its computation and some applications," *IEEE Transactions on Automatic Control*, vol.
-
-
- 25, pp. 164-176, 1980.
2. I. Xu and S. R. Van Doren, "Tracking equilibrium and nonequilibrium shifts in data with TREND," *Biophysical Journal*, vol. 112, pp. 224-233, 2017.
3. T. G. Kolda and B. W. Bader, "Tensor decompos

Acknowledgements

This work was authored by the National Renewalle Energy Laboratory, operated by Alliance for Successive Profer
(DOE) under Contract No. DE-AC36-08GO28308. Funding provided by the U.S. Department of Energy's Office of Energ the article do not necessarily represent the views of the DOE or the U.S. Government. The U.S. Government retains and the publisher, by accepting the
article for publication, acknowledges that the U.S. Government retains a

CNREL

